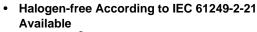


P-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}\left(\Omega\right)$	I _D (A) ^d	Q _g (Typ.)			
- 30	0.0125 at V _{GS} = - 10 V	- 11.6	22 nC			
	0.0180 at $V_{GS} = -4.5 \text{ V}$	- 10	22 110			

FEATURES



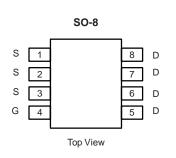


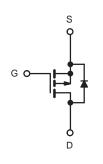
- 100 % R_g Tested
- 100 % UIS Tested





- · Load Switches
 - Notebook PCs
 - Desktop PCs





P-Channel MOSFET

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	- 30	V
Gate-Source Voltage		V _{GS}	± 20	
	T _C = 25 °C		- 11.6	
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C		- 10.5	
Continuous Diam Curient (1) = 150 °C)	T _A = 25 °C	l _D	- 8.7 ^{a, b}	
	T _A = 70 °C		- 7.7 ^{a, b}	
Pulsed Drain Current	I _{DM}	- 40	A	
Continuous Course Davis Diada Courset	T _C = 25 °C		- 4.6	
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	2.0 ^{a, b}	
Avalanche Current		I _{AS}	- 20	
Single-Pulse Avalanche Energy	L = 0.1 mH	E _{AS}	20	mJ
	T _C = 25 °C		5.6	
Mariana Dama Dissination	T _C = 70 °C		3.6	W
Maximum Power Dissipation	T _A = 25 °C	P _D	2.5 ^{a, b}	VV
	T _A = 70 °C		1.6 ^{a, b}	
Operating Junction and Storage Temperature Rang	T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{a, c}	t ≤ 10 s	R_{thJA}	39	50	°C/W	
Maximum Junction-to-Foot	Steady State	R_{thJF}	18	22	C/VV	

- a. Surface mounted on 1" x 1" FR4 board.
- c. Maximum under Steady State conditions is 85 °C/W. d. Based on $T_{\rm C}$ = 25 °C.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static				•			
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$			- 31		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			5.5			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	- 1.0		- 3.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = - 30 V, V _{GS} = 0 V			- 1 µA		
Zeio Gale voltage Diain Guiteit		V _{DS} = - 30 V, V _{GS} = 0 V, T _J = 55 °C			- 5	μΑ	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge -10 \text{ V}, V_{GS} = -10 \text{ V}$	- 30			Α	
Davis Course Co Otata Basista and	D	V _{GS} = - 10 V, I _D = - 10 A		0.011	0.0125		
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = -4.5 \text{ V}, I_D = -7 \text{ A}$		0.012	0.018	Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 10 V, I _D = - 10 A		23		S	
Dynamic ^b				•			
Input Capacitance	C _{iss}			1960		pF	
Output Capacitance	C _{oss}	$V_{DS} = -15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		380			
Reverse Transfer Capacitance	C _{rss}			325			
Total Gate Charge	$Q_g \qquad V_{DS} = -15 \text{ V, V}$	$V_{DS} = -15 \text{ V}, V_{GS} = -10 \text{ V}, I_{D} = -10 \text{ A}$		43	65	nC	
				22	33		
Gate-Source Charge	Q_{gs}	$V_{DS} = -15 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -10 \text{ A}$		6			
Gate-Drain Charge	Q _{gd}			11			
Gate Resistance	R_g	f = 1 MHz	0.3	1.3	2.5	Ω	
Turn-On Delay Time	t _{d(on)}			11	22		
Rise Time	t _r	V_{DD} = - 15 V, R_L = 3 Ω		13	25		
Turn-Off DelayTime	t _{d(off)}	$I_D \cong -5 \text{ A}, V_{GEN} = -10 \text{ V}, R_g = 1 \Omega$		32	50		
Fall Time	t _f			9	18	20	
Turn-On Delay Time	t _{d(on)}			44	70	ns	
Rise Time	t _r	V_{DD} = - 15 V, R_L = 3 Ω		100	160		
Turn-Off DelayTime	t _{d(off)}	$I_D \cong$ - 5 A, V_{GEN} = - 4.5 V, R_g = 1 Ω		28	50		
Fall Time	ì,	<u> </u>		15	30		
Drain-Source Body Diode Characterist	ics						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			- 4.6	۸	
Pulse Diode Forward Current	I _{SM}	-			- 50	A	
Body Diode Voltage	V _{SD}	I _S = -2 A, V _{GS} = 0 V		- 0.75	- 1.2	V	
Body Diode Reverse Recovery Time	t _{rr}	7 63		28	45	ns	
Body Diode Reverse Recovery Charge Q_{rr} Reverse Recovery Fall Time t_a $I_F = -2 \text{ A, dl/dt} = 100 \text{ A/µs, T}_J = 25$		1 2 A d1/d+ 400 A/::- T 05 00		20	40	nC	
		$I_F = -2 \text{ A}$, $\alpha I/\alpha t = 100 \text{ A/}\mu \text{s}$, $I_J = 25 \text{ °C}$		13		ns	
Reverse Recovery Rise Time	t _b	–		15			

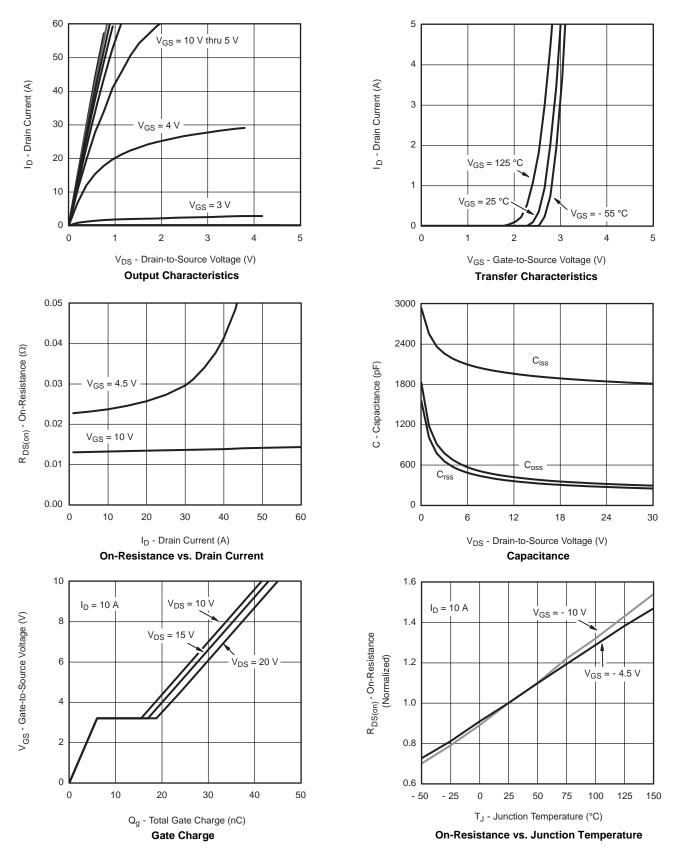
Notes:

- a. Pulse test; pulse width \leq 300 μ s, duty cycle \leq 2 %.
- b. Guaranteed by design, not subject to production testing.

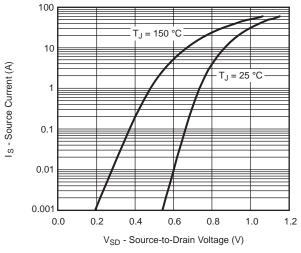
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

E-mail: China@VBsemi TEL:86-755-83251052

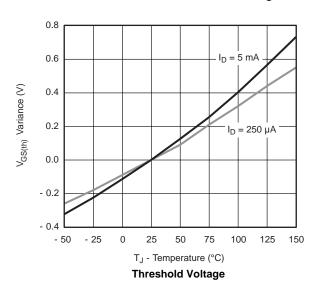


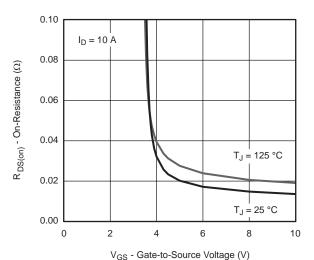




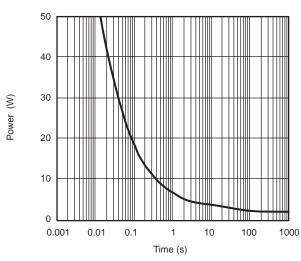


Source-Drain Diode Forward Voltage

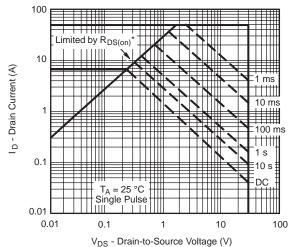




On-Resistance vs. Gate-to-Source Voltage



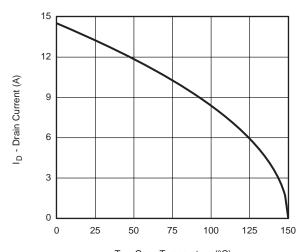
Single Pulse Power, Junction-to-Ambient



* V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified

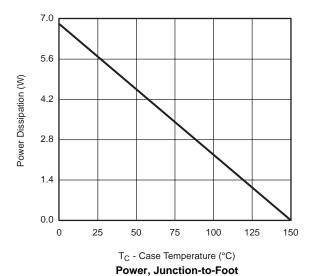
Safe Operating Area

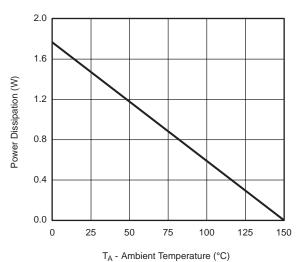




 $T_{\mbox{\scriptsize C}}$ - Case Temperature (°C)

Current Derating*

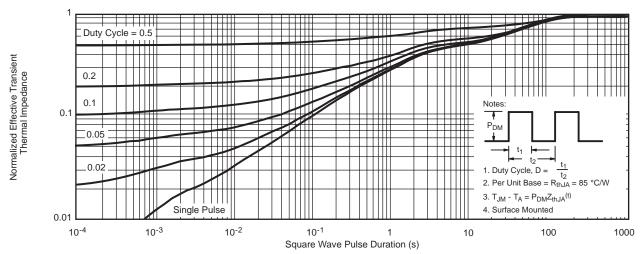




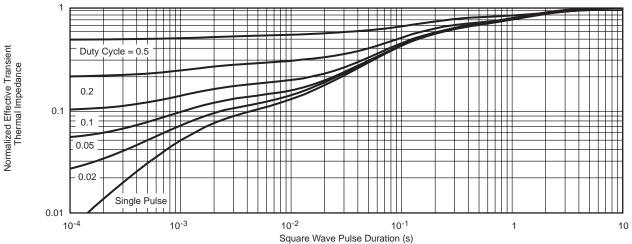
Power Derating, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





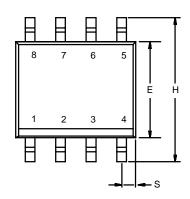
Normalized Thermal Transient Impedance, Junction-to-Ambient

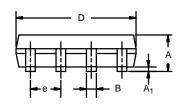


Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEADJEDEC Part Number: MS-012







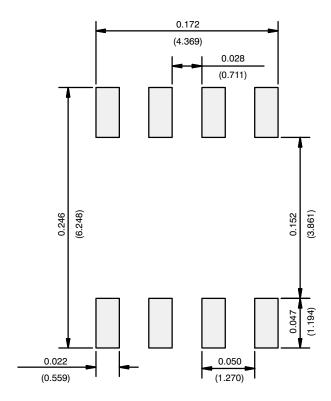
	MILLIMETERS		INC	HES		
DIM	Min	Max	Min	Max		
А	1.35	1.75	0.053	0.069		
A ₁	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
E	3.80	4.00	0.150	0.157		
е	1.27	BSC	0.050 BSC			
Н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
FCN: C-06527-Rev 11-Sen-06						

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)

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